

<b>Notice of References Cited</b>	Application/Control No. 10/584,037	Applicant(s)/Patent Under Reexamination BAKKERS ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Journal of Physical Chemistry B 2001, 105, 6838-6845 "Characterization of Ultrasmall CdS Nanoparticles Prepared by the Size-Selective Photoetching Technique" Tsukasa Torimoto, Hironori Kontani, Yoshihiro Shibutani, Susumu Kuwabata, Takao Sakata, Hirotaro Mori, and Hiroshi Yoneyama.
	V	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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